

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/735,884	PAIK ET AL.	
	Examiner LEE NGUYEN	Art Unit 2682	

SEARCHED			
Class	Subclass	Date	Examiner
455	415 416 435.1	5/27/2005	LN
	566 567		
379	93.23	5/27/2005	LN
	142.06		
	142.17		
348	14.02	5/27/2005	LN
	14.1		
UPDATE	SEARCH	1/29/2006	LN
	ALL ABOVE		